

NOISE

Look at a signal voltage $v(t)$ that interferes from a noise voltage v_n , which means that $v_{tot}(t) = v(t) + v_n(t)$. The power of the signal denotes P_{signal} and the power of the noise P_{noise} .

Following performance measures is defined:

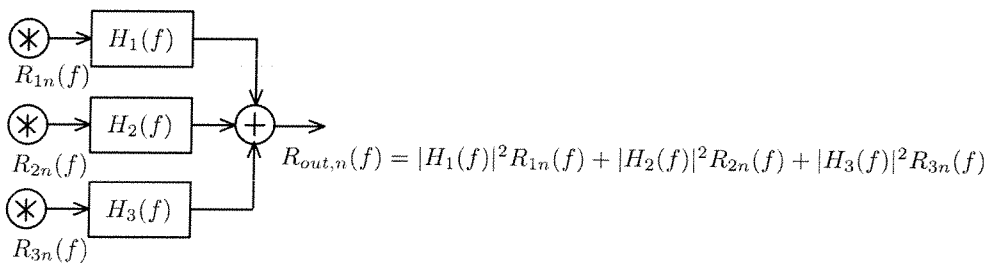
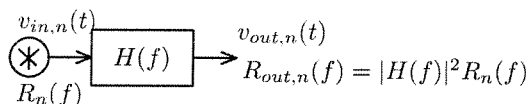
- Signal Noise Ratio, $SNR = 10 \cdot^{10} \log \frac{P_{signal}}{P_{noise}}$
- Dynamic Range, $DR = 20 \cdot^{10} \log \frac{|v_{in,max}(t)|}{|v_{in,min}(t)|}$
- If $|v_{in}(t)| > |v_{in,max}(t)|$ you get distorsion.
- If $|v_{in}(t)| < |v_{in,min}(t)|$ the signal gets drowned in the noise.
- Noise power, P_{noise} , defines as $P_{noise} = \frac{1}{T} \int_0^T v_n^2(t) dt$
- Also, if $V_n(f)$ is the Fourier transform of $v_n(t)$, $P_{noise} = \int_{-\infty}^{\infty} V_n^2(f) df$
- $V_n^2(f)$ is the spectral density $R_n(f)$ and $R_n(f)$ is the Fourier transform of the autocorrelation function $r_n(t)$. I.e. $V_n^2(f) = R_n(f) = \mathcal{F}\{r_n(t)\}$

If the input signal to a linear system, with transfer function $H(f)$, has a noise component with spectral density $R_n(f)$ the output signal will get a noise component with spectral density $R_{out,n}(f)$ and

$$R_{out,n}(f) = |H(f)|^2 R_n(f)$$

If we have say three systems, $H_1(f)$, $H_2(f)$ and $H_3(f)$ with noise, $R_{1n}(f)$, $R_{2n}(f)$ and $R_{3n}(f)$ respectively, on their inputs and the noise sources are *uncorrelated*, and if the output signals from the systems are added the spectral density of the output signal will be:

$$R_{out,n}(f) = |H_1(f)|^2 R_{1n}(f) + |H_2(f)|^2 R_{2n}(f) + |H_3(f)|^2 R_{3n}(f)$$



Noise bandwidth concept

Regard a one-pole system with transfer function

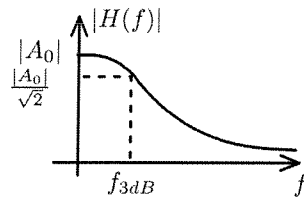
$$H(s) = \frac{A_0}{1 + \frac{s}{p_1}} \Rightarrow |H(f)| = \frac{|A_0|}{\sqrt{1 + \left(\frac{2\pi f}{p_1}\right)^2}}$$

This equation gives the 3dB cut-off frequency: $f_{3dB} = \frac{|p_1|}{2\pi}$.

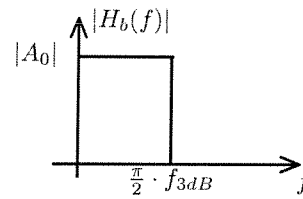
If you feed the system with *white noise*, that is noise with constant (independent of f) spectral density $R_i(f) = R_i$, the noise power on the output will be

$$\begin{aligned} P_{out,noise} &= \int_0^\infty |H(f)|^2 R_i df = R_i \int_0^\infty \frac{|A_0|^2}{1 + \left(\frac{2\pi f}{p_1}\right)^2} = R_i \cdot \frac{|A_0|^2 |p_1|}{2\pi} \left[\arctan \frac{2\pi f}{|p_1|} \right]_0^\infty \\ &= R_i \cdot \frac{|A_0|^2 |p_1|}{2\pi} \cdot \frac{\pi}{2} = R_i |A_0|^2 \cdot \frac{\pi}{2} \cdot \frac{|p_1|}{2\pi} = R_i |A_0|^2 \cdot \frac{\pi}{2} \cdot f_{3dB} \end{aligned}$$

If you have a *brick-wall filter* with $|H_b(f)| = |A_0|$ and bandwidth $\frac{\pi}{2} \cdot f_{3dB}$ you get the same power $P_{out,noise}$. Therefore $\frac{\pi}{2} \cdot f_{3dB}$ is said to be the **noise-bandwidth** of this one-pole system.



$$R_{out}(f) = R_i |H(f)|^2$$



$$R_{out}(f) = R_i |H_b(f)|^2$$

Noise in CMOS-circuits

Noise in CMOS-circuits is *inherent* noise, not *interference* noise. There are three different types of inherent noise.

- 1) Thermal noise - due to thermal excitation of charge carriers. Thermal noise is white noise.
- 2) Flicker noise - due to traps in the semiconductor that hold carriers, which normally gives the DC-current, for some while and then release them. (DC-current doesn't float smooth.) $R_n(f) \sim \frac{1}{f}$ (more accurate $R_n(f) \sim \frac{1}{f^\alpha}$ where $0.8 < \alpha < 1.3$).
- 3) Shot noise - DC-current is a result of individual carriers, which yields a current that actually is pulsed and not smooth.

Noise models CMOS: (Regard the saturated region)

Flicker noise (spektral density $V_g^2(f) = \frac{K}{WLC_{ox}f}$) and thermal noise (spektral density $I_d^2(f) = 4kT \frac{2}{3} g_m$) dominates in CMOS-circuits.

As $i_d(t) \approx g_m v_{gs}(t)$ then $I_d(f) \approx g_m V_{gs}(f)$ and the thermal noise with spektral density $I_d^2(f) = 4kT \frac{2}{3} g_m$ can be transformed to an equivalent noise voltage on the input with the spektral density $V_{gs}^2(f) = 4kT \frac{2}{3} \frac{1}{g_m}$. $V_{gs}^2(f)$ and $V_g^2(f)$ are uncorrelated and can thus be added.


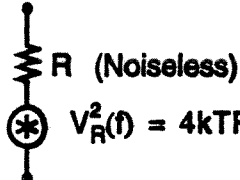
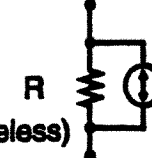

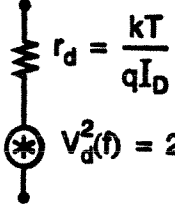
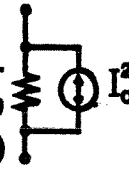

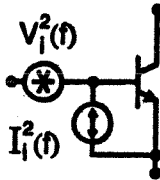

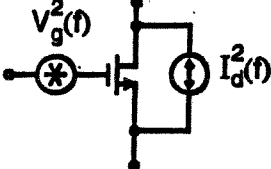
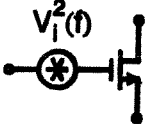

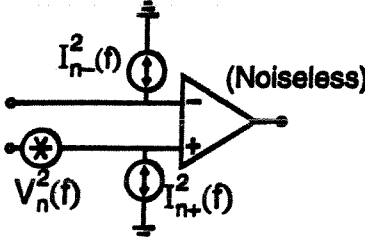
Element	Noise Models	
<p>Resistor</p> 	 <p>R (Noiseless) $V_R^2(f) = 4kTR$</p>	 <p>(Noiseless) $I_R^2(f) = \frac{4kT}{R}$</p>
<p>Diode</p>  <p>(Forward biased)</p>	 <p>$r_d = \frac{kT}{qI_D}$ (Noiseless) $V_d^2(f) = 2kTr_d$</p>	 <p>(Noiseless) $I_d^2(f) = 2qI_D$</p>
<p>BJT</p>  <p>(Active region)</p>	 <p>(Noiseless) $V_i^2(f)$ $I_i^2(f)$</p>	<p>$V_i^2(f) = 4kT\left(r_b + \frac{1}{2g_m}\right)$ $I_i^2(f) = 2q\left(I_B + \frac{KI_B}{f} + \frac{I_C}{ \beta(f) ^2}\right)$</p>
<p>MOSFET</p>  <p>(Active region)</p>	 <p>$V_g^2(f)$ $I_d^2(f)$ $V_g^2(f) = \frac{K}{WLC_{ox}f}$ $I_d^2(f) = 4kT\left(\frac{2}{3}\right)g_m$</p>	 <p>(Noiseless) $V_i^2(f) = 4kT\left(\frac{2}{3}\right)\frac{1}{g_m} + \frac{K}{WLC_{ox}f}$ Simplified model for low and moderate frequencies</p>
<p>Opamp</p> 	 <p>(Noiseless) $V_n(f), I_{n-}(f), I_{n+}(f)$ — Values depend on opamp — Typically, all uncorrelated</p>	

Fig. 4.11 Circuit elements and their noise models. Note that capacitors and inductors do not generate noise.

DISTORSION

- **Harmonic distortion**

A result of non-linearities of the circuit (system). This means that e.g. a sinusoidal input signal $x(t)$ doesn't generate a sinusoidal output signal. Instead it gives a periodical non-sinusoidal output signal $y(t)$. $y(t)$ can be described by a fourier serie.

$$x(t) = \hat{X} \sin \omega_1 t \Rightarrow y(t) = Y_0 + \sum_{k=1}^{\infty} \hat{Y}_k \sin(k\omega_1 t + \varphi_k)$$

Different distortion metrics:

THD (Total Harmonic Distorsion)

$$THD = \frac{(\sum_{k=2}^{\infty} Y_{ke}^2)^{1/2}}{(\sum_{k=1}^{\infty} Y_{ke}^2)^{1/2}} = \frac{(Y_e^2 - Y_0^2 - Y_{1e}^2)^{1/2}}{(Y_e^2 - Y_0^2)^{1/2}}$$

$$Y_{ke} = \frac{\hat{Y}_k}{\sqrt{2}} \text{ and } Y_e^2 = \frac{1}{T} \int_T |y(t)|^2 dt$$

$$SFDR \text{ (Spurious-Free Dynamic Range)} = P_1 - \max\{P_k\}_{k \geq 2} \text{ [dB]}$$

- **Bandwidth distortion, D_b**

Reason: The bandwidth of the reconstructed signal is lower than the bandwidth of the original signal.

$$D_b = \frac{W_{cb}}{W_x}$$

$$\text{Energi of the original signal: } W_x = \int_{-\infty}^{\infty} |x(t)|^2 dt = \frac{1}{2\pi} \int_{-\infty}^{\infty} |X(\omega)|^2 d\omega$$

Energi of the error-signal caused by bandwidth distortion:

$$W_{eb} = \frac{1}{2\pi} \int_{|\omega| > \pi f_s} |X(\omega)|^2 d\omega$$

- **Aliasing distortion, D_v**

Caused by undersampling ($f_s < 2f_{max}$), when different periods of spectrum from the sampled signal are overlapping.

$$D_v = \frac{W_{ev}}{W_x}$$

Energi of error-signal caused by aliasing:

$$W_{ev} = \frac{1}{2\pi} \int_{-\pi f_s}^{\pi f_s} \left| \sum_{k \neq 0} X(\omega - k2\pi f_s) \right|^2 d\omega$$